



superior performance.
powerful technology.

Transmission Level HTS Fault Current Limiter



Dr. Juan-Carlos Llambes

C.S. Weber, D.W. Hazelton, M. Marchevsky, Y.Y. Xie, V. Selvamanickam

Applied Superconductivity Conference (Session 4LY07)

Chicago, Illinois

August 21, 2008

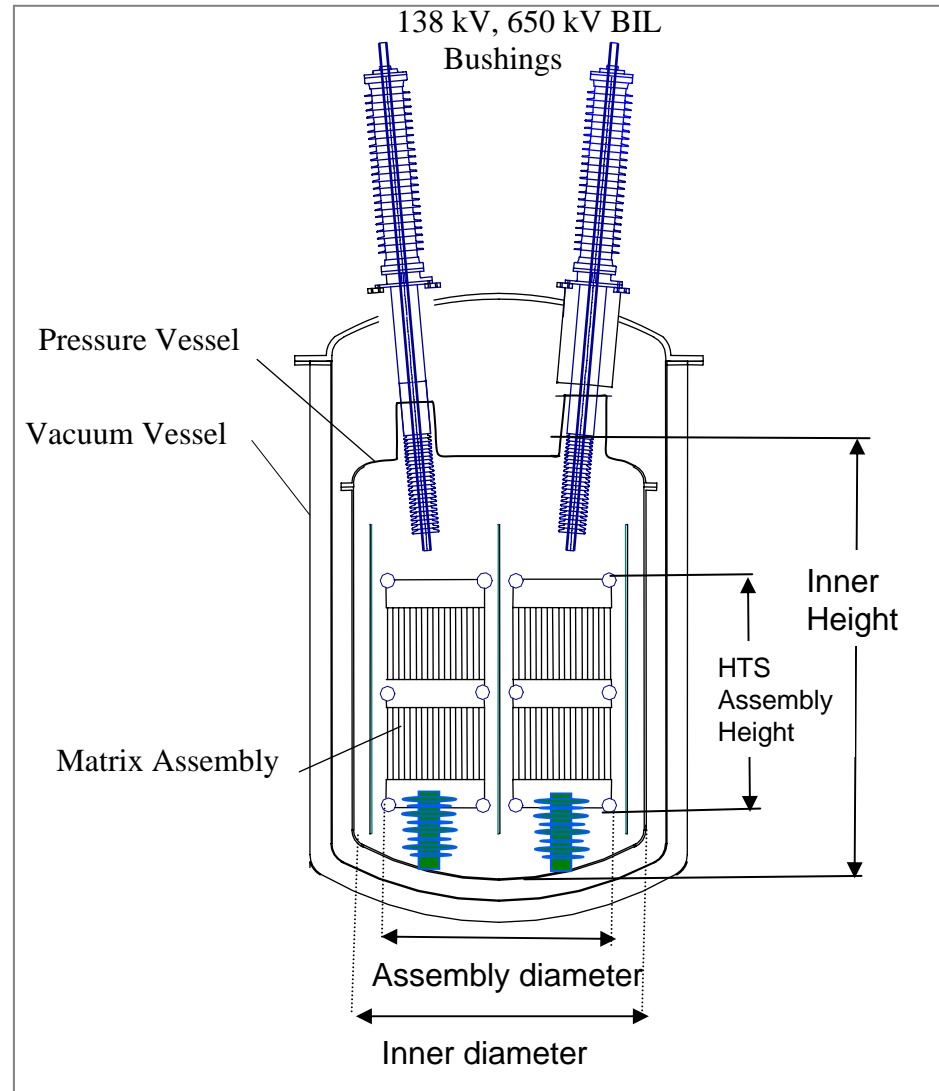
SFCL program overview

Partners



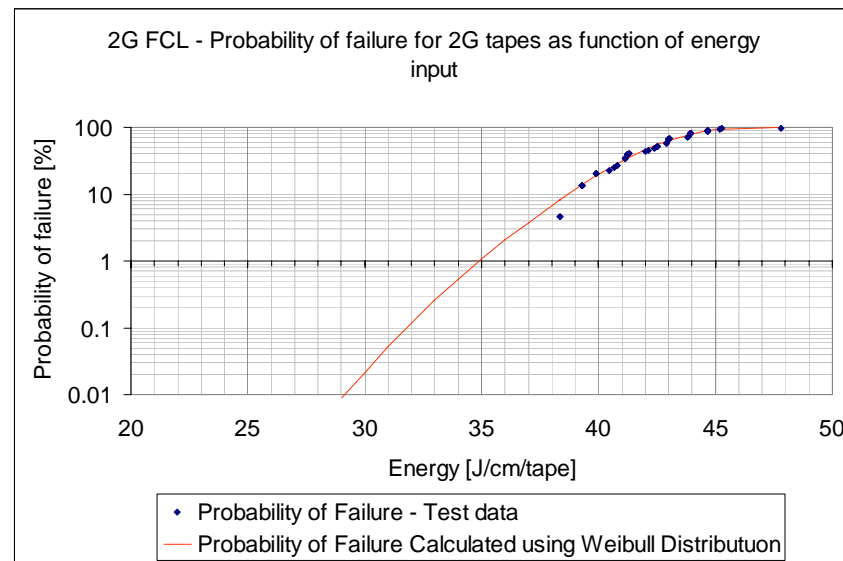
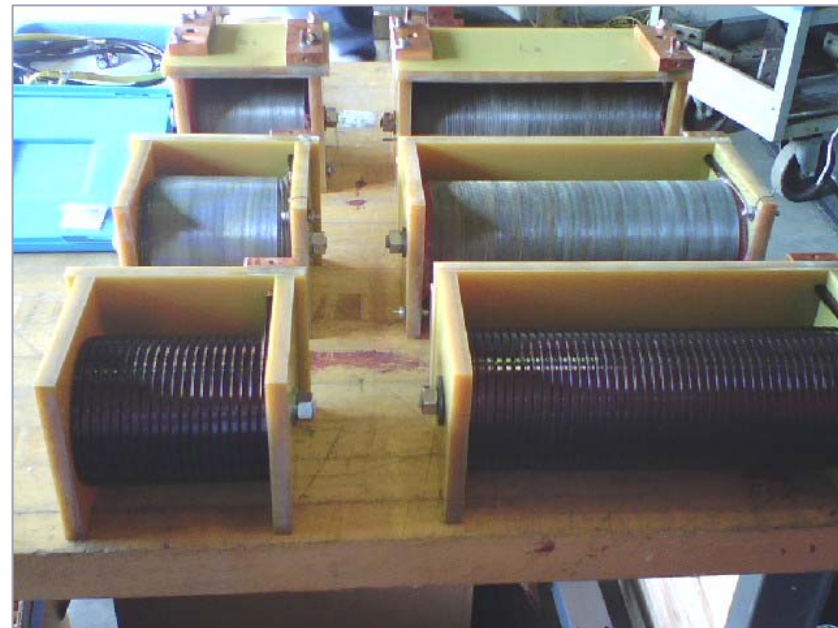
Specifications

- YBCO based, resistive type FCL
- 138 kV class device
- Fault Current – 13.8 kA
- Load Current – 1,200 A_{rms}
- Design fault current – 37 kA
- Design device response – Recover to superconducting state after a fault carrying full load current



Prior accomplishments

- Proof-of-Concept demonstrated
 - MCP 2212 (2004)
 - 2G YBCO (2006)
- Beta device testing specifications established
- Completed design and testing of HV bushings (SEI)
- Investigated several ‘engineered’ 2G architectures for improved RUL
- Design and laboratory testing of shunt coils to withstand high fault transient loads
- Thermal simulation of RUL process
- Weibull plots of ‘standard’ 2G failures
- Conceptual CRS & vessel design
- Investigated LN₂ dielectric properties

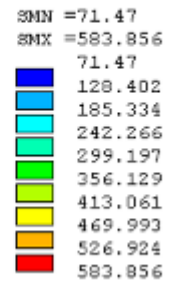
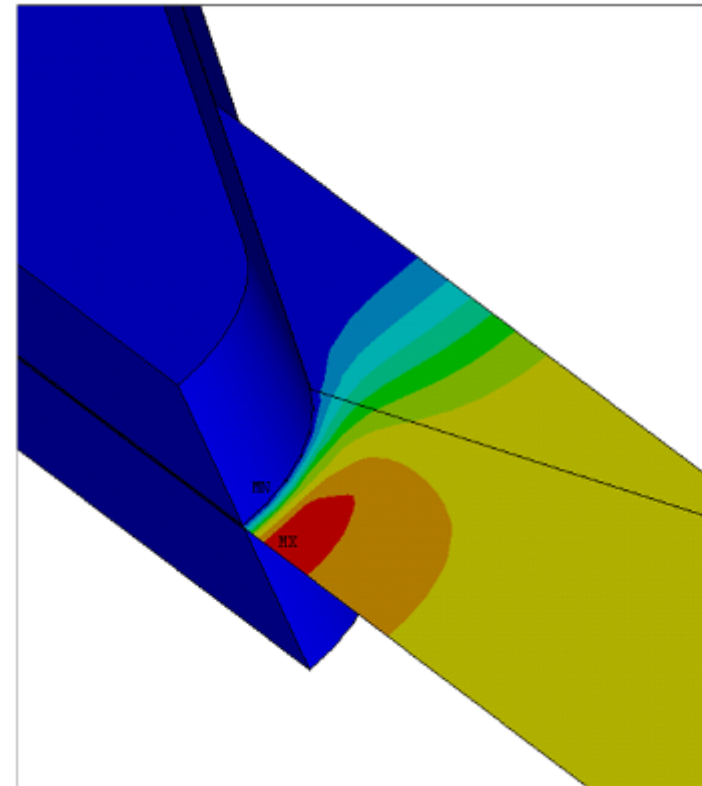
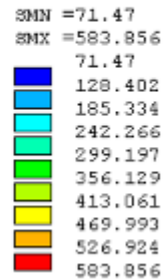
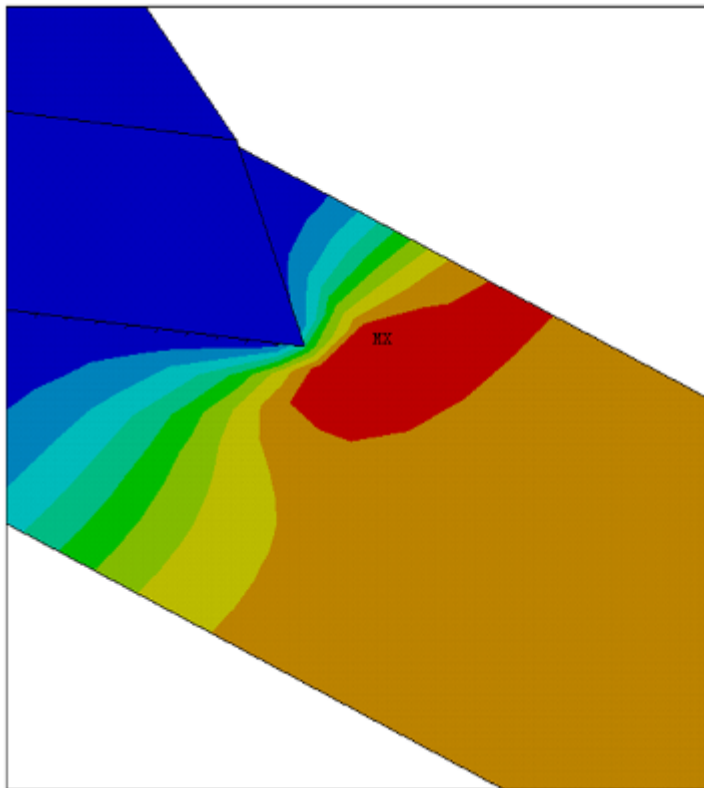


Improvements to shunt coil and contact design

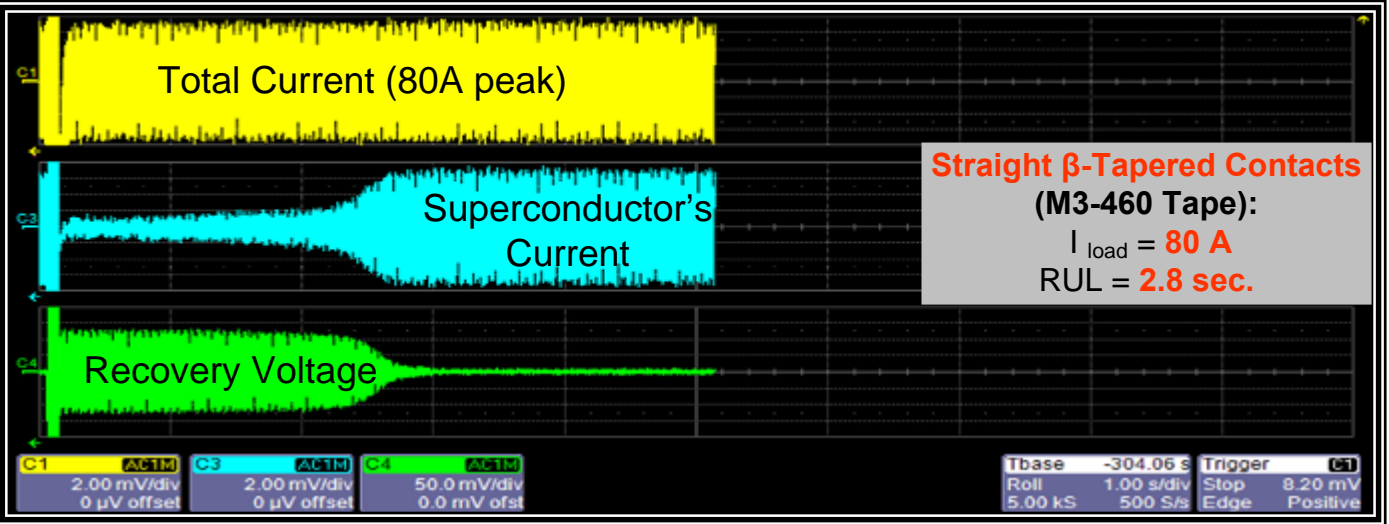
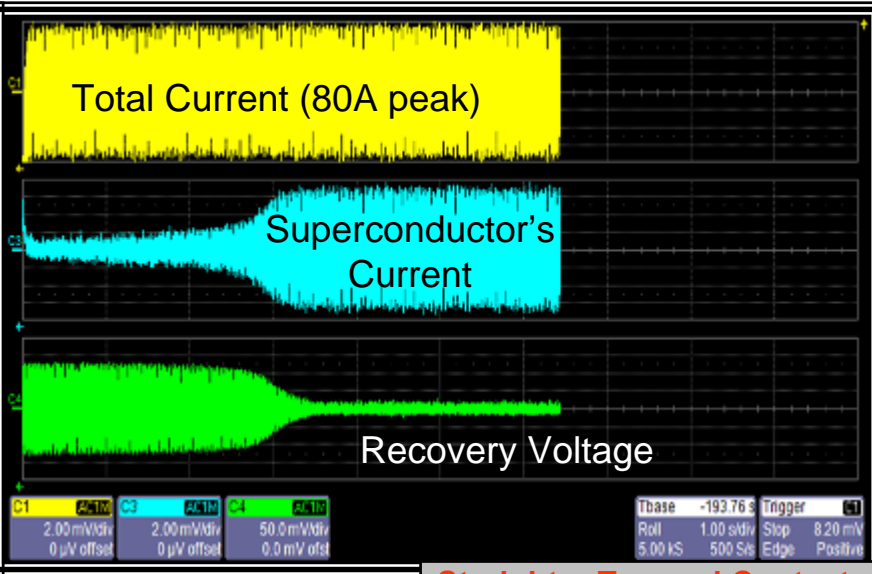
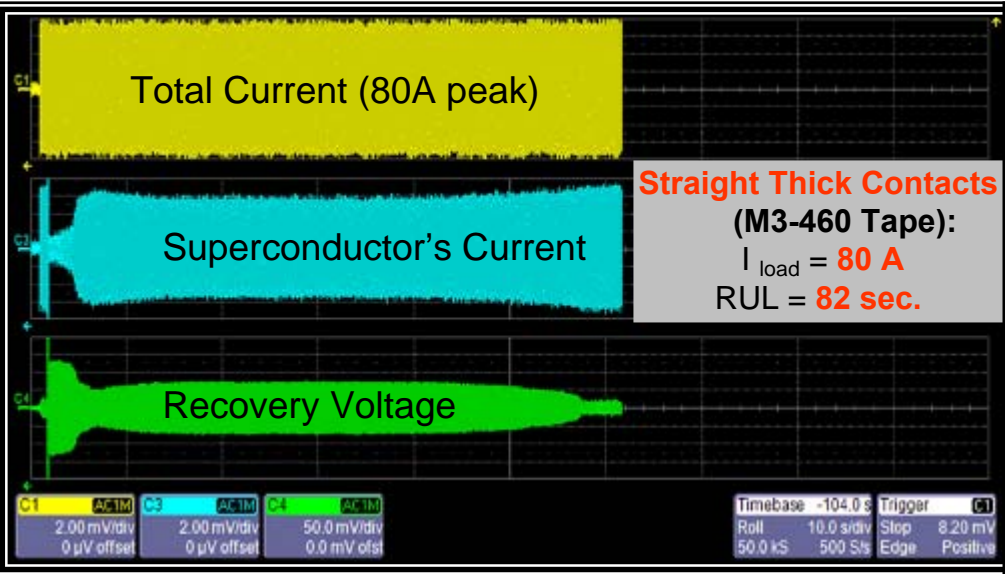
- Shunt coil improvements:
 - Manufacturing improvements (easier assembly, more robust coil)
 - Mechanical strength
 - Multi-Layer winding (size reduction)
- Connector improvements:
 - Shape optimization to avoid contact hotspots
 - Improvement in RUL Time
 - Improvement in RUL Current
 - Improvement in consistency of contact resistance



Tape heating near contact during fault impacts RUL



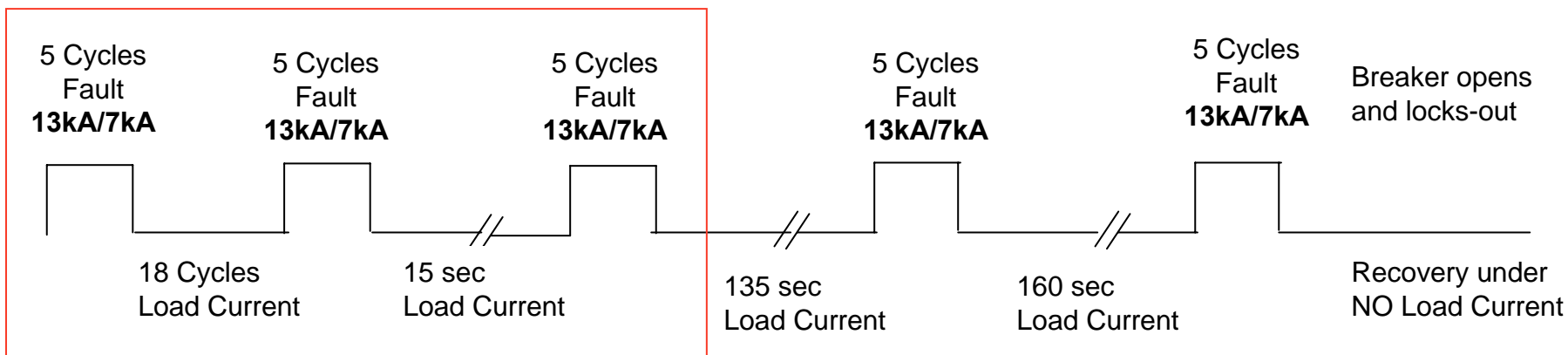
Correlation between different contact geometries



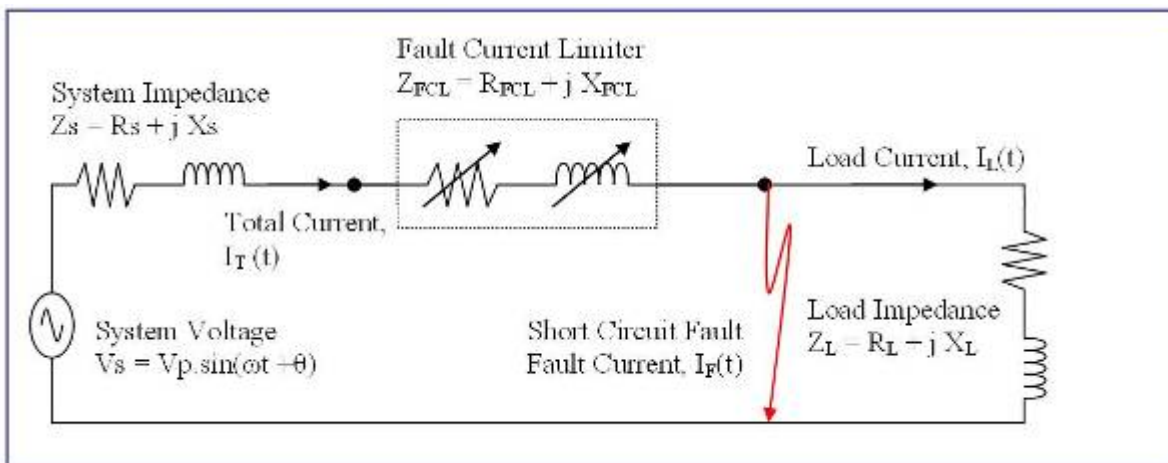
Straight α -Tapered Contacts (M3-460 Tape):
 $I_{load} = 80 \text{ A}$
 RUL = **3.5 sec.**

Recent KEMA tests

- Recent rounds of KEMA testing focused on critical AEP reclosure sequence on an HTS element



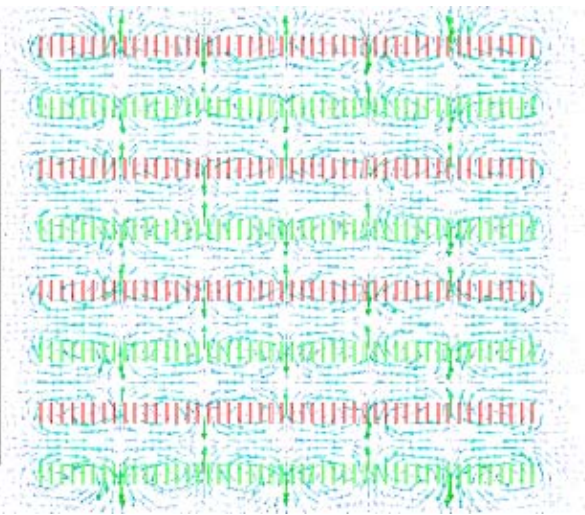
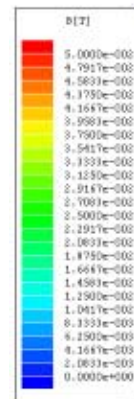
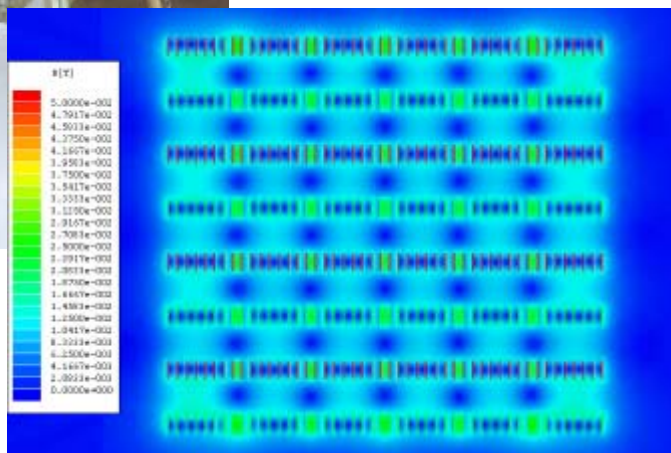
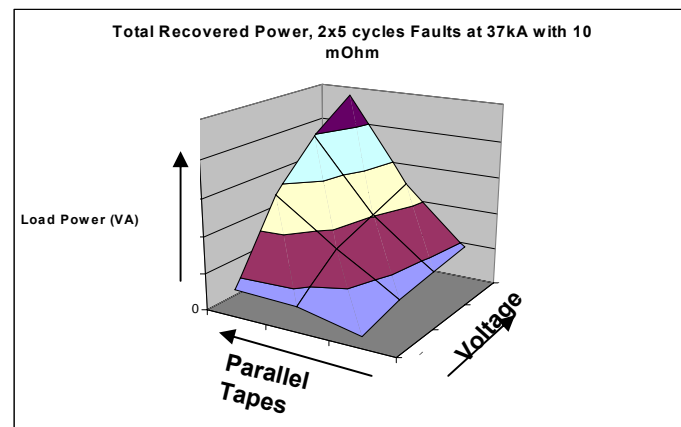
- Straight elements were used
- Improved connector designs were used
- “Standard”, pre-qualified tapes were used
- Test Dates: May 2008, July 2008



2G RUL capabilities tested at KEMA

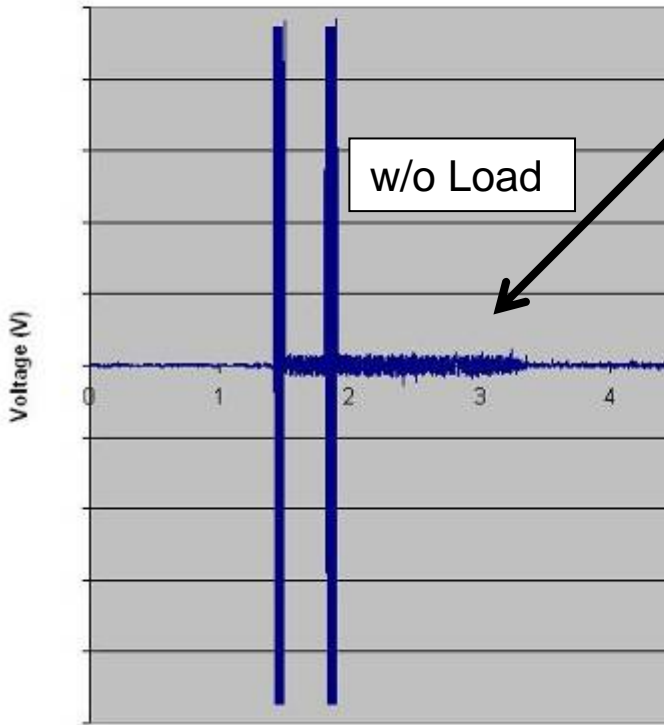


- 'Standard' SC12100 2G wire used
- Test conditions
 - 37 kA fault
 - follows AEP sequence
- Test variables
 - Shunt impedance
 - Number of parallel tapes
 - System voltage (v/cm/tape)
 - Load Current

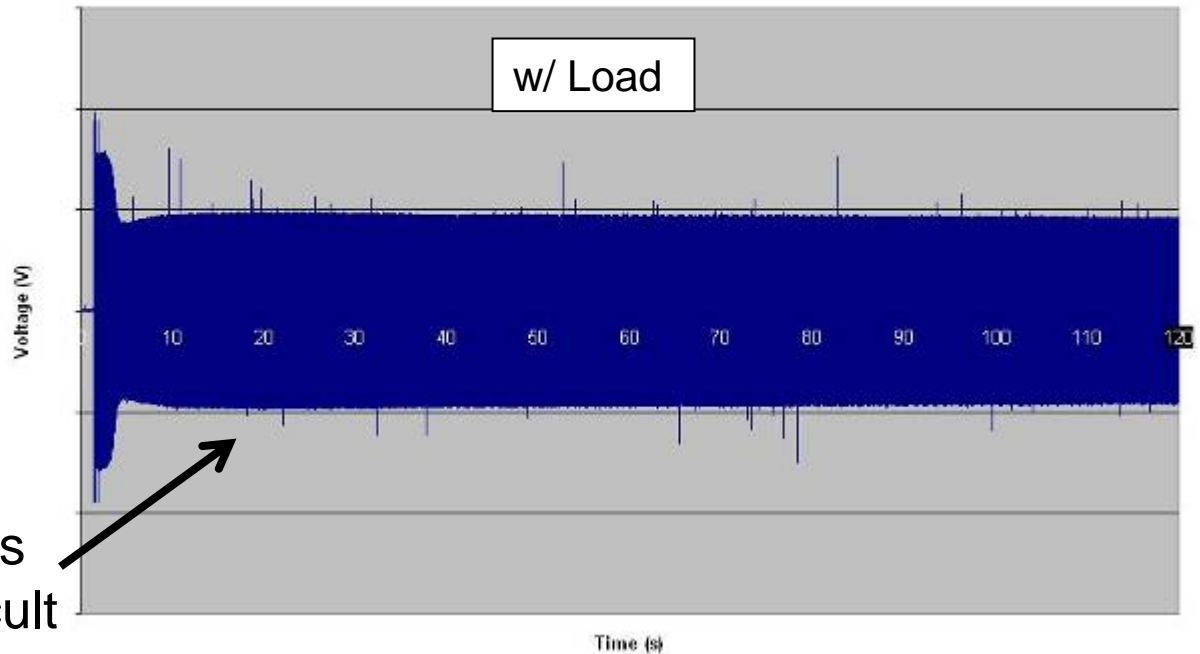


Achieving RUL is a difficult task

Without load current recovery is very fast



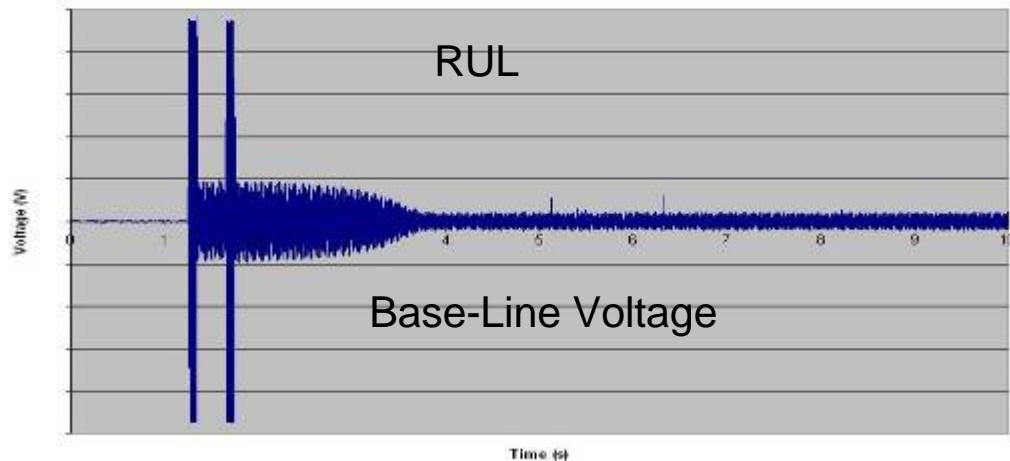
Recovery Time for AEP Sequence of 2 Asymmetrical Faults of 37kA 5 Cycles duration each, 1.5 times the Base-line Impedance, using the maximum Voltage and number of Tapes (With RUL)



Adding load current makes recovery much more difficult

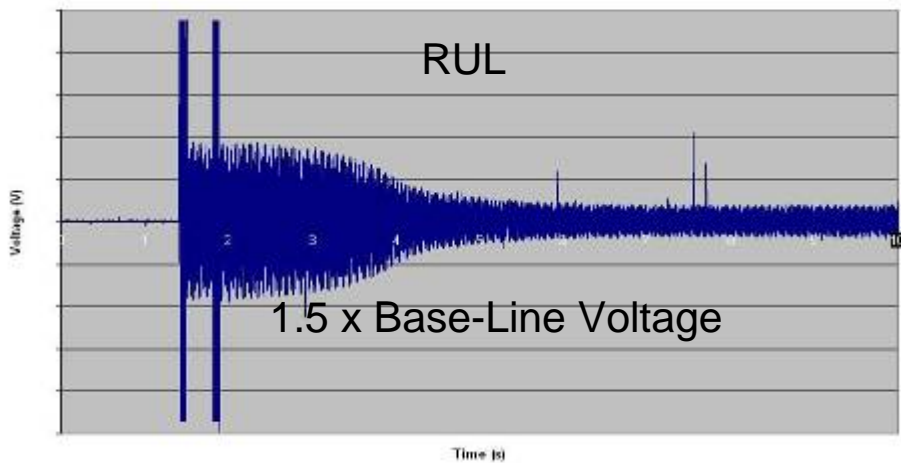
Electrical stress on the tapes can limit RUL

Recovery Time for AEP Sequence of 2 Asymmetrical Faults of 37kA 5 Cycles duration each, Base-line Impedance, using Base-line Voltage and number of parallel Tapes (With RUL)

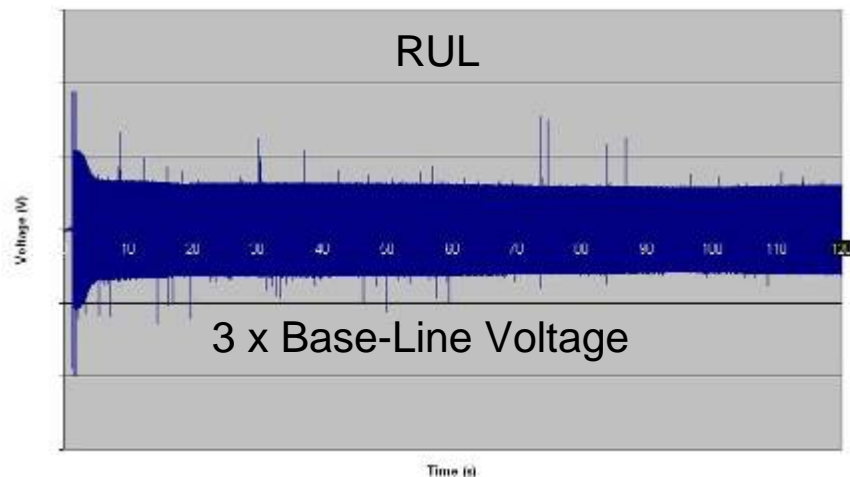


- RUL time can be affected by increasing the V/cm on the tape
- Limits of the design optimization are understood

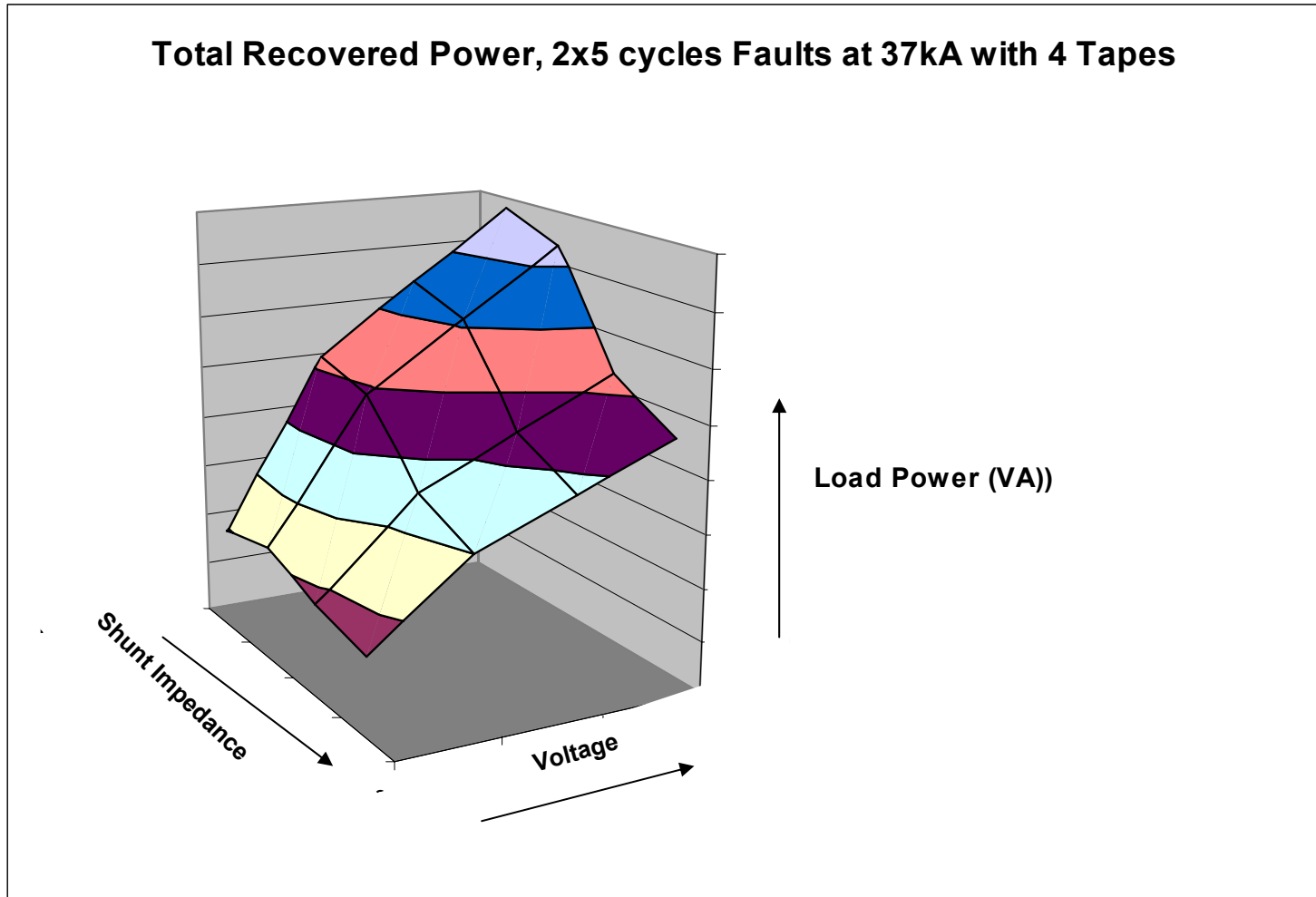
Recovery Time for AEP Sequence of 2 Asymmetrical Faults of 37kA 5 Cycles duration each, Base-line Impedance, 2 times the Base-line Voltage, same number of Tapes (With RUL)



Recovery Time for AEP Sequence of 2 Asymmetrical Faults of 37kA 5 Cycles duration each, Base-line Impedance, using the maximum Voltage and number of parallel Tapes (With RUL)



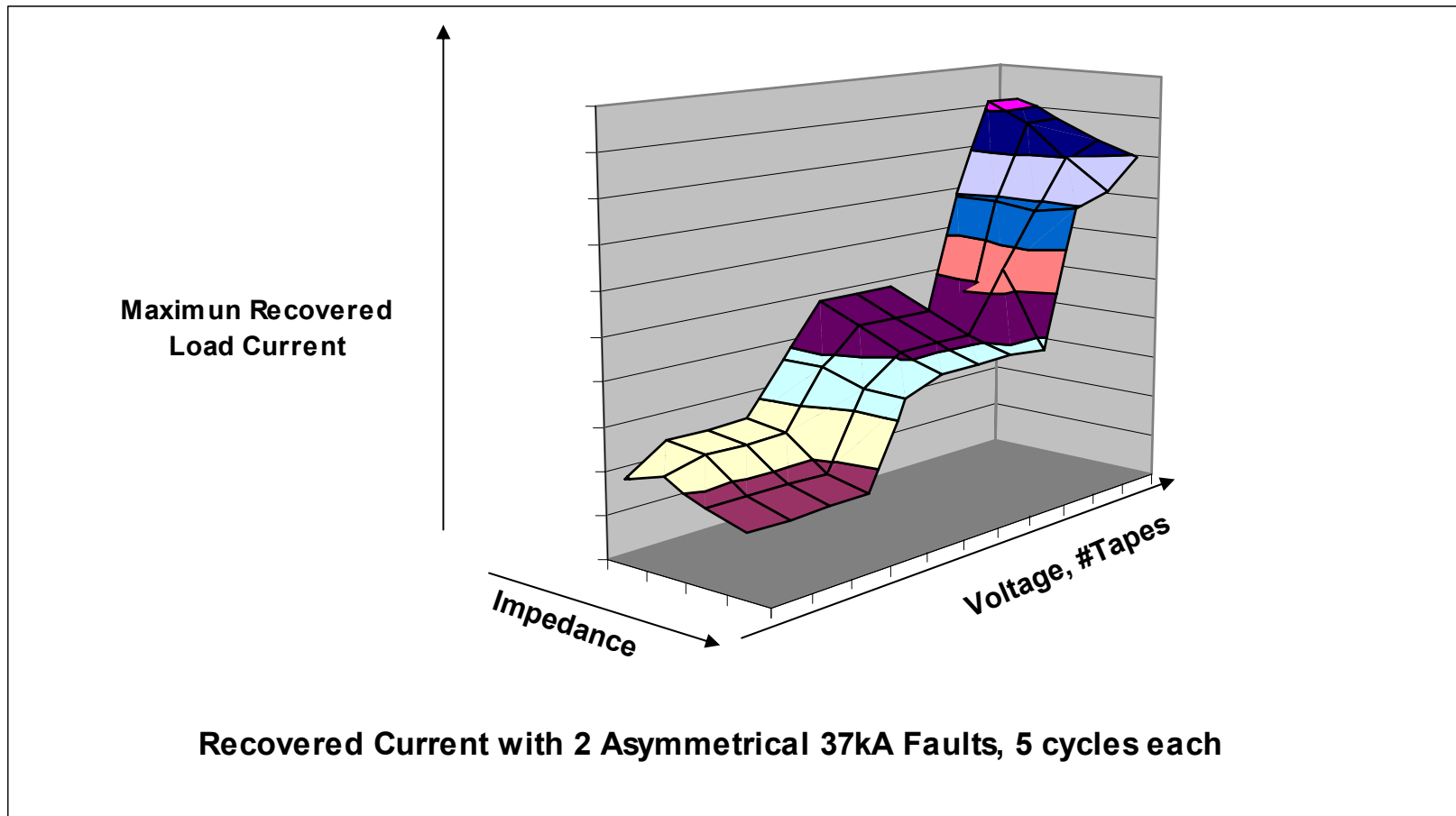
Factors impacting RUL defined by test results



Sample surface plot of RUL conditions

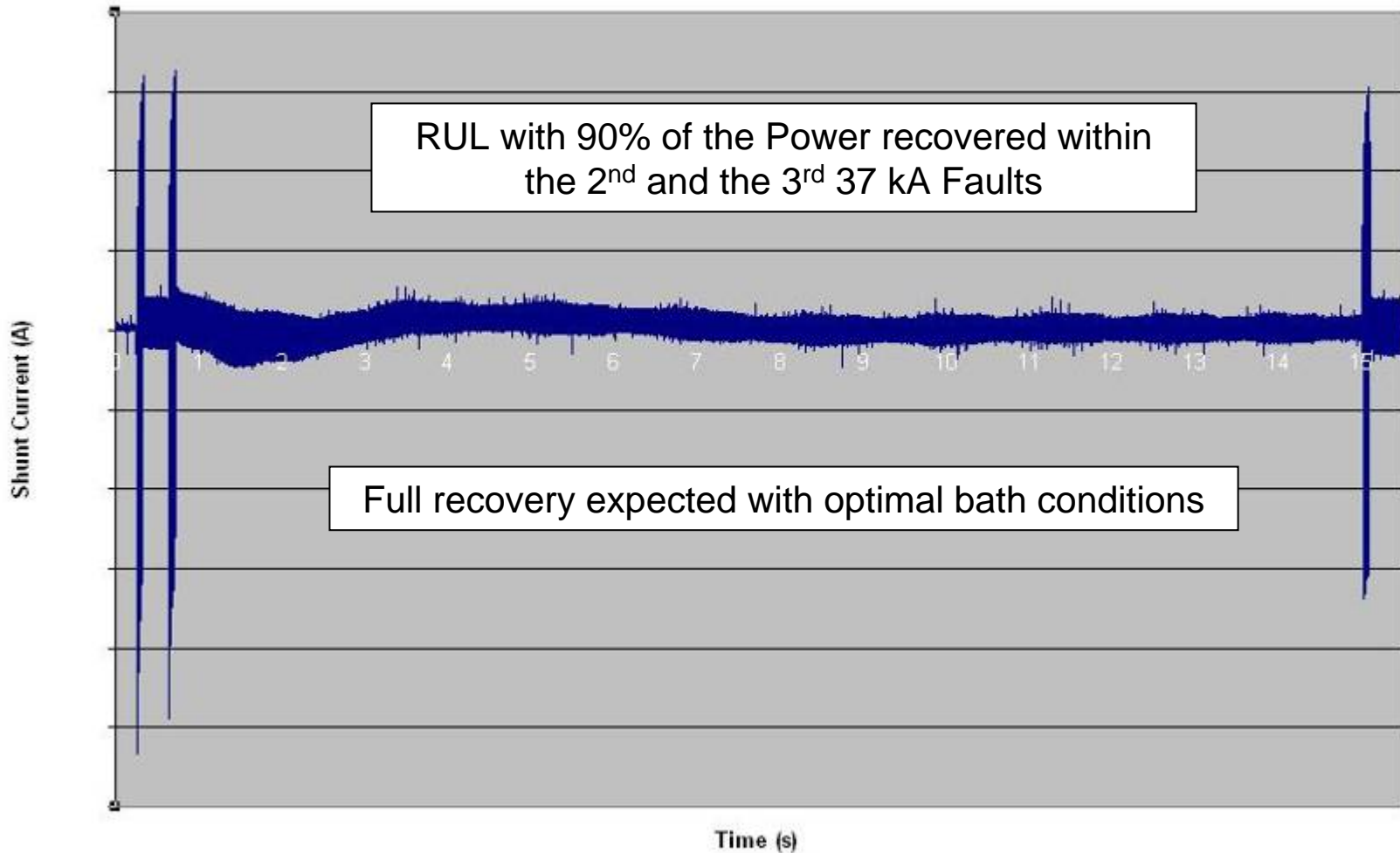
Ability to predict RUL over wide design space

Maximum Load Current as a function of shunt impedance, operating voltage & number of tapes



Worst case conditions at Tidd can achieve RUL

Recovery Time for AEP Sequence of 3 Asymmetrical Faults of 37kA peak with 5 Cycles each, 1200A Load Current



Thank You for your attention!

For more information:

www.superpower-inc.com

or

jllambes@superpower-inc.com